

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRS-d encoded:
				5 *
				6 * E63F VECTOR STORE RIGHTMOST WITH LENGTH (reg)
				7 *
				8 * also tests
				9 * E637 VLRLR - VECTOR LOAD RIGHTMOST WITH LENGTH (reg)
				10 *
				11 * James Wekel June 2024
				12 *****
				13
				14 *****
				15 *
				16 * basic instruction tests
				17 *
				18 *****
				19 * This program tests proper functioning of the z/arch E6 VRS-d vector
				20 * store rightmost with length (reg). Exceptions are not tested.
				21 *
				22 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				23 * obvious coding errors. None of the tests are thorough. They are
				24 * NOT designed to test all aspects of any of the instructions.
				25 *
				26 *****
				27 *
				28 * *Testcase zvector-e6-09-VSTRLR: VECTOR E6 VRS-d VSTRLR instruction
				29 * *
				30 * * Zvector E6 tests for VRS-d encoded instructions:
				31 * *
				32 * * E63F VECTOR STORE RIGHTMOST WITH LENGTH (reg)
				33 * *
				34 * * # -----
				35 * * # This tests only the basic function of the instruction.
				36 * * # Exceptions are NOT tested.
				37 * * # -----
				38 * *
				39 * main size 2
				40 * numcpu 1
				41 * sysclear
				42 * archlvl z/Arch
				43 *
				44 * diag8cmd enable # (needed for messages to Hercules console)
				45 * loadcore "\$(testpath)/zvector-e6-09-VSTRLR.core" 0x0
				46 * diag8cmd disable # (reset back to default)
				47 *
				48 * *Done
				49 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				51 *****
				52 * FCHECK Macro - Is a Facility Bit set?
				53 *
				54 * If the facility bit is NOT set, an message is issued and
				55 * the test is skipped.
				56 *
				57 * Fcheck uses R0, R1 and R2
				58 *
				59 * eg. FCHECK 134, 'vector-packed-decimal'
				60 *****
				61 MACRO
				62 FCHECK &BITNO, &NOTSETMSG
				63 . * &BITNO : facility bit number to check
				64 . * &NOTSETMSG : 'facility name'
				65 LCLA &FBBYTE Facility bit in Byte
				66 LCLA &FBBIT Facility bit within Byte
				67
				68 LCLA &L(8)
				69 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				70
				71 &FBBYTE SETA &BITNO/8
				72 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				73 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				74
				75 B X&SYSNDX
				76 * Fcheck data area
				77 * skip messgae
				78 SKT&SYSNDX DC C' Skipping tests: '
				79 DC C&NOTSETMSG
				80 DC C' facility (bit &BITNO) is not installed.'
				81 SKL&SYSNDX EQU *-SKT&SYSNDX
				82 * facility bits
				83 DS FD gap
				84 FB&SYSNDX DS 4FD
				85 DS FD gap
				86 *
				87 X&SYSNDX EQU *
				88 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				89 STFLE FB&SYSNDX get facility bits
				90
				91 XGR R0, R0
				92 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				93 N R0, =F' &FBBIT' is bit set?
				94 BNZ XC&SYSNDX
				95 *
				96 * facility bit not set, issue message and exit
				97 *
				98 LA R0, SKL&SYSNDX message length
				99 LA R1, SKT&SYSNDX message address
				100 BAL R2, MSG
				101
				102 B EOJ
				103 XC&SYSNDX EQU *
				104 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				126 *****
				127 * The actual "ZVE6TST" program itself...
				128 *****
				129 *
				130 * Architecture Mode: z/Arch
				131 * Register Usage:
				132 *
				133 * R0 (work)
				134 * R1-4 (work)
				135 * R5 Testing control table - current test base
				136 * R6- R7 (work)
				137 * R8 First base register
				138 * R9 Second base register
				139 * R10 Third base register
				140 * R11 E6TEST call return
				141 * R12 E6TESTS register
				142 * R13 (work)
				143 * R14 Subroutine call
				144 * R15 Secondary Subroutine call or work
				145 *
				146 *****
00000200		00000200		148 USING BEGIN, R8 FIRST Base Register
00000200		00001200		149 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		150 USING BEGIN+8192, R10 THIRD Base Register
				151
00000200	0580			152 BEGIN BALR R8, 0 Initalize FIRST base register
00000202	0680			153 BCTR R8, 0 Initalize FIRST base register
00000204	0680			154 BCTR R8, 0 Initalize FIRST base register
				155
00000206	4190 8800		00000800	156 LA R9, 2048(, R8) Initalize SECOND base register
0000020A	4190 9800		00000800	157 LA R9, 2048(, R9) Initalize SECOND base register
				158
0000020E	41A0 9800		00000800	159 LA R10, 2048(, R9) Initalize THIRD base register
00000212	41A0 A800		00000800	160 LA R10, 2048(, R10) Initalize THIRD base register
				161
00000216	B600 82A4		000004A4	162 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 82A5		000004A5	163 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 82A5		000004A5	164 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 82A4		000004A4	165 LCTL R0, R0, CTLR0 Reload updated CRO
				166
				167 *****
				168 * Is Vector packed-decimal facility installed (bit 134)
				169 *****
				170
00000226	47F0 80B0		000002B0	171 FCHECK 134, ' vector-packed- decimal '
				172+ B X0001
				173+ * Fcheck data area
				174+ * skip messgae
0000022A	40404040 40404040			175+SKT0001 DC C' Skipping tests: '
00000244	A58583A3 96996097			176+ DC C' vector-packed-decimal '
00000259	40868183 899389A3			177+ DC C' facility (bit 134) is not installed. '
		00000054 00000001		178+SKL0001 EQU *- SKT0001
				179+ * facility bits
00000280	00000000 00000000			180+ DS FD gap
00000288	00000000 00000000			181+FB0001 DS 4FD

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						231 *****	
						232 * result not as expected:	
						233 * issue message with test number, instruction under test	
						234 * and instruction l2	
						235 *****	
0000031E	4820	5004		0000031E	00000001	236 FAILMSG EQU *	
00000322	4E20	8E74			00000004	237 LH R2, TNUM	get test number and convert
00000326	D211	8E5E 8E48		0000105E	00001074	238 CVD R2, DECNUM	
0000032C	DE11	8E5E 8E74		0000105E	00001074	239 MWC PRT3, EDIT	
00000332	D202	8E18 8E6B		00001018	0000106B	240 ED PRT3, DECNUM	
						241 MWC PRTNUM(3), PRT3+13	fill in message with test #
						242	
00000338	D207	8E33 5010		00001033	00000010	243 MWC PRTNAME, OPNAME	fill in message with instruction
						244	
0000033E	B982	0022				245 XGR R2, R2	get l2 as U32
00000342	5820	5008			00000008	246 L R2, L2	
00000346	4E20	8E74			00001074	247 CVD R2, DECNUM	and convert
0000034A	D211	8E5E 8E48		0000105E	00001048	248 MWC PRT3, EDIT	
00000350	DE11	8E5E 8E74		0000105E	00001074	249 ED PRT3, DECNUM	
00000356	D202	8E44 8E6B		00001044	0000106B	250 MWC PRTL2(3), PRT3+13	fill in message with l2 field
						251	
0000035C	4100	0040			00000040	252 LA R0, PRTLNG	message length
00000360	4110	8E08			00001008	253 LA R1, PRTLNE	messagfe address
00000364	45F0	8186			00000386	254 BAL R15, RPTERROR	
						256 *****	
						257 * continue after a failed test	
						258 *****	
00000368	5800	82B4		00000368	00000001	259 FAILCONT EQU *	
0000036C	5000	8E00			000004B4	260 L R0, =F' 1'	set GLOBAL failed test indicator
					00001000	261 ST R0, FAILED	
						262	
00000370	41C0	C004			00000004	263 LA R12, 4(0, R12)	next test address
00000374	47F0	80DC			000002DC	264 B NEXTE6	
						266 *****	
						267 * end of testing; set ending psw	
						268 *****	
00000378	5810	8E00		00000378	00000001	269 ENDTEST EQU *	
0000037C	1211				00001000	270 L R1, FAILED	did a test fail?
0000037E	4780	8288			00000488	271 LTR R1, R1	
00000382	47F0	82A0			000004A0	272 BZ E0J	No, exit
						273 B FAILTEST	Yes, exit with BAD PSW
						274	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				339	*****
				340	* Normal completion or Abnormal termination PSWs
				341	*****
00000478	00020001 80000000			343	E0JPSW DC OD' 0' , X' 0002000180000000' , AD(0)
00000488	B2B2 8278		00000478	345	E0J LPSWE E0JPSW Normal completion
00000490	00020001 80000000			347	FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')
000004A0	B2B2 8290		00000490	349	FAILTEST LPSWE FAILPSW Abnormal termination
				351	*****
				352	* Working Storage
				353	*****
000004A4	00000000			355	CTLRO DS F CRO
000004A8	00000000			356	DS F
000004AC				358	LTORG , Literals pool
000004AC	00000002			359	=F' 2'
000004B0	000013B4			360	=A(E6TESTS)
000004B4	00000001			361	=F' 1'
000004B8	0000			362	=H' 0'
000004BA	005F			363	=AL2(L' MSGMSG)
				364	
				365	* some constants
				366	
	00000400	00000001		367	K EQU 1024 One KB
	00001000	00000001		368	PAGE EQU (4*K) Size of one page
	00010000	00000001		369	K64 EQU (64*K) 64 KB
	00100000	00000001		370	MB EQU (K*K) 1 MB
				371	
	AABBCCDD	00000001		372	REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		373	REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
-----	-------------	-------	-------	------

503 *****

```
504 *      PTTABLE Macro to generate table of pointers to individual tests
```

505 *****8*****4*****

506

507 MACRO

508 PTTABLE

509 **GBLA** **&TNUM**

510 **LCLA** **&CUR**

511 &CUR SETA 1

512 . *

513 TTABLE DS OF

514 . LOOP ANOP

515 . *

516	DC	A(T&CUR)	address of test
-----	----	----------	-----------------

517 . *

518 &CUR SETA &CUR+1

```
519      AIF  (&CUR LE &TNUM). LOOP
```

520 *

521	DC	A(0)	END OF TABLE
-----	----	------	--------------

522 DC A(0)

523 . *

524 **MEND**

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				526 *****	
				527 * E6 VRS_D tests	
				528 *****	
00001110		00000000	000013DF	529 ZVE6TST CSECT ,	
				530 DS 0F	
				532 PRINT DATA	
				533 *	
				534 * E63F VECTOR STORE RIGHTMDST WITH LENGTH (reg)	
				535 *	
				536 * VRS_D instr, l2	
				537 * followed by	
				538 * v1 - 16 byte expected result	
				539 * source - 16 byte source from which to get	
				540 * L2+1 (up to 16) bytes	
				541	
				542 * -----	
				543 * VSTRLR - VECTOR STORE RIGHTMDST WITH LENGTH (reg)	
				544 * -----	
				545 * VSTRLR simple	
				546	
				547 VRS_D VSTRLR, 0	1-byte
00001110				548+ DS 0FD	
00001110		00001110		549+ USING *, R5	base for test data and test routine
00001110	00001130			550+T1 DC A(X1)	address of test routine
00001114	0001			551+ DC H' 1'	test number
00001116	00			552+ DC X' 00'	
00001117	00			553+ DC X' 00'	
00001118	00000000			554+ DC F' 0'	l2
0000111C	0000115C			555+EA2_1 DC A(RE1+16)	addr of 16-byte source
00001120	E5E2E3D9 D3D94040			556+ DC CL8' VSTRLR'	instruction name
00001128	00000010			557+ DC A(16)	result length
0000112C	0000114C			558+REA1 DC A(RE1)	result address
				559+*	INSTRUCTION UNDER TEST ROUTINE
00001130				560+X1 DS 0F	
00001130	5810 5008		00000008	561+ L R1, L2	get number of bytes to load / store
00001134	5820 500C		0000000C	562+ L R2, EADDR	get address of source
00001138	E601 2000 1037		00000000	563+ VLRLR V1, R1, 0(R2)	load some bytes
0000113E	5810 5008		00000008	564+ L R1, L2	get number of bytes to store
00001142	E601 8EA0 103F		000010A0	565+ VSTRLR V1, R1, V1OUTPUT	test instruction
00001148	07FB			566+ BR R11	return
0000114C				567+RE1 DC 0F	
0000114C				568+ DROP R5	
0000114C	22BBBBBB BBBBBBBB			569 DC XL16' 22BBBBBBBBBBBBBBBBBBBBBBBBBBBBBBBB'	V1
00001154	BBBBBBBB BBBBBBBB				
0000115C	22000000 00000000			570 DC XL16' 220000000000000000000000000023C'	source
00001164	00000000 0000023C				
				571	
				572 VRS_D VSTRLR, 1	
00001170				573+ DS 0FD	
00001170		00001170		574+ USING *, R5	base for test data and test routine
00001170	00001190			575+T2 DC A(X2)	address of test routine
00001174	0002			576+ DC H' 2'	test number
00001176	00			577+ DC X' 00'	
00001177	00			578+ DC X' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001178	00000001			579+	DC	F' 1'	12
0000117C	000011BC			580+EA2_2	DC	A(RE2+16)	addr of 16-byte source
00001180	E5E2E3D9 D3D94040			581+	DC	CL8' VSTRLR'	instruction name
00001188	00000010			582+	DC	A(16)	result length
0000118C	000011AC			583+REA2	DC	A(RE2)	result address
				584+*			INSTRUCTION UNDER TEST ROUTINE
00001190				585+X2	DS	OF	
00001190	5810 5008		00000008	586+	L	R1, L2	get number of bytes to load / store
00001194	5820 500C		0000000C	587+	L	R2, EADDR	get address of source
00001198	E601 2000 1037		00000000	588+	VLRLR	V1, R1, 0(R2)	load some bytes
0000119E	5810 5008		00000008	589+	L	R1, L2	get number of bytes to store
000011A2	E601 8EA0 103F		000010A0	590+	VSTRLR	V1, R1, V10UTPUT	test instruction
000011A8	07FB			591+	BR	R11	return
000011AC				592+RE2	DC	OF	
000011AC				593+	DROP	R5	
000011AC	2233BBBB BBBB BBBB			594	DC	XL16' 2233BBBBBBBBBBBBBBBBBBBBBBBBBBBBBBBB'	V1
000011B4	BBBBBBBB BBBB BBBB						
000011BC	22330000 00000000			595	DC	XL16' 2233000000000000000000000000023C'	source
000011C4	00000000 0000023C						
				596			
				597	VRS_D	VSTRLR, 5	
000011D0				598+	DS	OFD	
000011D0		000011D0		599+	USING	*, R5	base for test data and test routine
000011D0	000011F0			600+T3	DC	A(X3)	address of test routine
000011D4	0003			601+	DC	H' 3'	test number
000011D6	00			602+	DC	X' 00'	
000011D7	00			603+	DC	X' 00'	
000011D8	00000005			604+	DC	F' 5'	12
000011DC	0000121C			605+EA2_3	DC	A(RE3+16)	addr of 16-byte source
000011E0	E5E2E3D9 D3D94040			606+	DC	CL8' VSTRLR'	instruction name
000011E8	00000010			607+	DC	A(16)	result length
000011EC	0000120C			608+REA3	DC	A(RE3)	result address
				609+*			INSTRUCTION UNDER TEST ROUTINE
000011F0				610+X3	DS	OF	
000011F0	5810 5008		00000008	611+	L	R1, L2	get number of bytes to load / store
000011F4	5820 500C		0000000C	612+	L	R2, EADDR	get address of source
000011F8	E601 2000 1037		00000000	613+	VLRLR	V1, R1, 0(R2)	load some bytes
000011FE	5810 5008		00000008	614+	L	R1, L2	get number of bytes to store
00001202	E601 8EA0 103F		000010A0	615+	VSTRLR	V1, R1, V10UTPUT	test instruction
00001208	07FB			616+	BR	R11	return
0000120C				617+RE3	DC	OF	
0000120C				618+	DROP	R5	
0000120C	22334455 6677BBBB			619	DC	XL16' 223344556677BBBBBBBBBBBBBBBBBBBB'	V1
00001214	BBBBBBBB BBBB BBBB						
0000121C	22334455 66778800			620	DC	XL16' 2233445566778800000000000000023C'	source
00001224	00000000 0000023C						
				621			
				622	VRS_D	VSTRLR, 14	
00001230				623+	DS	OFD	
00001230		00001230		624+	USING	*, R5	base for test data and test routine
00001230	00001250			625+T4	DC	A(X4)	address of test routine
00001234	0004			626+	DC	H' 4'	test number
00001236	00			627+	DC	X' 00'	
00001237	00			628+	DC	X' 00'	
00001238	0000000E			629+	DC	F' 14'	12
0000123C	0000127C			630+EA2_4	DC	A(RE4+16)	addr of 16-byte source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001240	E5E2E3D9 D3D94040			631+	DC	CL8' VSTRLR'	instruction name
00001248	00000010			632+	DC	A(16)	result length
0000124C	0000126C			633+REA4	DC	A(RE4)	result address
				634+*			INSTRUCTION UNDER TEST ROUTINE
00001250				635+X4	DS	OF	
00001250	5810 5008		00000008	636+	L	R1, L2	get number of bytes to load / store
00001254	5820 500C		0000000C	637+	L	R2, EADDR	get address of source
00001258	E601 2000 1037		00000000	638+	VLRLR	V1, R1, 0(R2)	load some bytes
0000125E	5810 5008		00000008	639+	L	R1, L2	get number of bytes to store
00001262	E601 8EA0 103F		000010A0	640+	VSTRLR	V1, R1, V10UTPUT	test instruction
00001268	07FB			641+	BR	R11	return
0000126C				642+RE4	DC	OF	
0000126C				643+	DROP	R5	
0000126C	22334455 66778800			644	DC	XL16' 2233445566778800000000000000002BB'	V1
00001274	00000000 000002BB						
0000127C	22334455 66778800			645	DC	XL16' 22334455667788000000000000000023C'	source
00001284	00000000 0000023C						
				646			
00001290				647	VRS_D	VSTRLR, 15	
00001290		00001290		648+	DS	OFD	
00001290	000012B0			649+	USING	*, R5	base for test data and test routine
00001294	0005			650+T5	DC	A(X5)	address of test routine
00001294	0005			651+	DC	H' 5'	test number
00001296	00			652+	DC	X' 00'	
00001297	00			653+	DC	X' 00'	
00001298	0000000F			654+	DC	F' 15'	12
0000129C	000012DC			655+EA2_5	DC	A(RE5+16)	addr of 16-byte source
000012A0	E5E2E3D9 D3D94040			656+	DC	CL8' VSTRLR'	instruction name
000012A8	00000010			657+	DC	A(16)	result length
000012AC	000012CC			658+REA5	DC	A(RE5)	result address
				659+*			INSTRUCTION UNDER TEST ROUTINE
000012B0				660+X5	DS	OF	
000012B0	5810 5008		00000008	661+	L	R1, L2	get number of bytes to load / store
000012B4	5820 500C		0000000C	662+	L	R2, EADDR	get address of source
000012B8	E601 2000 1037		00000000	663+	VLRLR	V1, R1, 0(R2)	load some bytes
000012BE	5810 5008		00000008	664+	L	R1, L2	get number of bytes to store
000012C2	E601 8EA0 103F		000010A0	665+	VSTRLR	V1, R1, V10UTPUT	test instruction
000012C8	07FB			666+	BR	R11	return
000012CC				667+RE5	DC	OF	
000012CC				668+	DROP	R5	
000012CC	22334455 66778800			669	DC	XL16' 22334455667788000000000000000023C'	V1
000012D4	00000000 0000023C						
000012DC	22334455 66778800			670	DC	XL16' 22334455667788000000000000000023C'	source
000012E4	00000000 0000023C						
				671			
000012F0				672	VRS_D	VSTRLR, 32	check r3>15
000012F0		000012F0		673+	DS	OFD	
000012F0	00001310			674+	USING	*, R5	base for test data and test routine
000012F4	0006			675+T6	DC	A(X6)	address of test routine
000012F4	0006			676+	DC	H' 6'	test number
000012F6	00			677+	DC	X' 00'	
000012F7	00			678+	DC	X' 00'	
000012F8	00000020			679+	DC	F' 32'	12
000012FC	0000133C			680+EA2_6	DC	A(RE6+16)	addr of 16-byte source
00001300	E5E2E3D9 D3D94040			681+	DC	CL8' VSTRLR'	instruction name
00001308	00000010			682+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000130C	0000132C			683+REA6 684+*	DC	A(RE6)	result address INSTRUCTION UNDER TEST ROUTINE
00001310				685+X6	DS	OF	
00001310	5810 5008		00000008	686+	L	R1, L2	get number of bytes to load / store
00001314	5820 500C		0000000C	687+	L	R2, EADDR	get address of source
00001318	E601 2000 1037		00000000	688+	VLRLR	V1, R1, 0(R2)	load some bytes
0000131E	5810 5008		00000008	689+	L	R1, L2	get number of bytes to store
00001322	E601 8EA0 103F		000010A0	690+	VSTRLR	V1, R1, V10UTPUT	test instruction
00001328	07FB			691+	BR	R11	return
0000132C				692+RE6	DC	OF	
0000132C				693+	DROP	R5	
0000132C	22334455 66778800			694	DC	XL16' 22334455667788000000000000000023C'	V1
00001334	00000000 0000023C						
0000133C	22334455 66778800			695	DC	XL16' 22334455667788000000000000000023C'	source
00001344	00000000 0000023C						
				696			
				697	VRS_D	VSTRLR, 999	check r3>15
00001350				698+	DS	OFD	
00001350		00001350		699+	USING	*, R5	base for test data and test routine
00001350	00001370			700+T7	DC	A(X7)	address of test routine
00001354	0007			701+	DC	H' 7'	test number
00001356	00			702+	DC	X' 00'	
00001357	00			703+	DC	X' 00'	
00001358	000003E7			704+	DC	F' 999'	12
0000135C	0000139C			705+EA2_7	DC	A(RE7+16)	addr of 16-byte source
00001360	E5E2E3D9 D3D94040			706+	DC	CL8' VSTRLR'	instruction name
00001368	00000010			707+	DC	A(16)	result length
0000136C	0000138C			708+REA7	DC	A(RE7)	result address
				709+*			INSTRUCTION UNDER TEST ROUTINE
00001370				710+X7	DS	OF	
00001370	5810 5008		00000008	711+	L	R1, L2	get number of bytes to load / store
00001374	5820 500C		0000000C	712+	L	R2, EADDR	get address of source
00001378	E601 2000 1037		00000000	713+	VLRLR	V1, R1, 0(R2)	load some bytes
0000137E	5810 5008		00000008	714+	L	R1, L2	get number of bytes to store
00001382	E601 8EA0 103F		000010A0	715+	VSTRLR	V1, R1, V10UTPUT	test instruction
00001388	07FB			716+	BR	R11	return
0000138C				717+RE7	DC	OF	
0000138C				718+	DROP	R5	
0000138C	99334455 66778800			719	DC	XL16' 99334455667788000000000000009023C'	V1
00001394	00000000 0009023C						
0000139C	99334455 66778800			720	DC	XL16' 99334455667788000000000000009023C'	source
000013A4	00000000 0009023C						
				721			
000013AC	00000000			722	DC	F' 0'	END OF TABLE
000013B0	00000000			723	DC	F' 0'	
				724 *			
				725 *	table of pointers to individual load test		
				726 *			
000013B4				727 E6TESTS	DS	OF	
				728	PTTABLE		
000013B4				729+TTABLE	DS	OF	
000013B4	00001110			730+	DC	A(T1)	address of test
000013B8	00001170			731+	DC	A(T2)	address of test
000013BC	000011D0			732+	DC	A(T3)	address of test
000013C0	00001230			733+	DC	A(T4)	address of test
000013C4	00001290			734+	DC	A(T5)	address of test

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT	
					744	*****
					745	* Register equates
					746	*****
			00000000	00000001	748 R0	EQU 0
			00000001	00000001	749 R1	EQU 1
			00000002	00000001	750 R2	EQU 2
			00000003	00000001	751 R3	EQU 3
			00000004	00000001	752 R4	EQU 4
			00000005	00000001	753 R5	EQU 5
			00000006	00000001	754 R6	EQU 6
			00000007	00000001	755 R7	EQU 7
			00000008	00000001	756 R8	EQU 8
			00000009	00000001	757 R9	EQU 9
			0000000A	00000001	758 R10	EQU 10
			0000000B	00000001	759 R11	EQU 11
			0000000C	00000001	760 R12	EQU 12
			0000000D	00000001	761 R13	EQU 13
			0000000E	00000001	762 R14	EQU 14
			0000000F	00000001	763 R15	EQU 15
					765	*****
					766	* Register equates
					767	*****
			00000000	00000001	769 V0	EQU 0
			00000001	00000001	770 V1	EQU 1
			00000002	00000001	771 V2	EQU 2
			00000003	00000001	772 V3	EQU 3
			00000004	00000001	773 V4	EQU 4
			00000005	00000001	774 V5	EQU 5
			00000006	00000001	775 V6	EQU 6
			00000007	00000001	776 V7	EQU 7
			00000008	00000001	777 V8	EQU 8
			00000009	00000001	778 V9	EQU 9
			0000000A	00000001	779 V10	EQU 10
			0000000B	00000001	780 V11	EQU 11
			0000000C	00000001	781 V12	EQU 12
			0000000D	00000001	782 V13	EQU 13
			0000000E	00000001	783 V14	EQU 14
			0000000F	00000001	784 V15	EQU 15
			00000010	00000001	785 V16	EQU 16
			00000011	00000001	786 V17	EQU 17
			00000012	00000001	787 V18	EQU 18
			00000013	00000001	788 V19	EQU 19
			00000014	00000001	789 V20	EQU 20
			00000015	00000001	790 V21	EQU 21

DESC	SYMBOL	SIZE	POS	ADDR
------	--------	------	-----	------

Entry: 0

Image Region CSECT	IMAGE	5088	0000-13DF	0000-13DF
		5088	0000-13DF	0000-13DF
	ZVE6TST	5088	0000-13DF	0000-13DF

STMT	FILE NAME
------	-----------

```
1 /home/tn529/sharedvfp/tests/zvector-e6-09-VSTRLR.asm
```

**** NO ERRORS FOUND ****